



Guest Editorial

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Guest Editorial

These Proceedings contain a collection of papers based on the invited, oral, and poster presentations at the Joint International Conference SPM-2019-RCWDFM combining the 3rd International Conference “Scanning Probe Microscopy” (SPM), the 4th Russia-China Workshop on Dielectric and Ferroelectric Materials (RCWDFM), and International Youth Conference “Functional Imaging of Nanomaterials”, which was held in Ekaterinburg, Russia, August 25–28, 2019.

Joint International Conference SPM-2019-RCWDFM covered a wide range of scientific topics.

SPM Topics:

- SPM in materials science
- PFM, MFM, KPFM, SNOM, ESM, SEM, and related techniques
- Tip-enhanced phenomena
- Probe lithography and nano-indentation
- Ferroelectrics, piezoelectrics, and ionic conductors
- Multiferroic phenomena and magnetoelectric coupling on the nanoscale
- Interface and domain engineering
- Biocompatible & organic materials
- 1D and 2D nanostructured materials
- Theory, modeling, and data processing

RCWDFM Topics:

- High-performance piezo-/ferroelectric materials and devices
- Thin films, single crystals, interfaces and nanoscale materials
- Multiferroic materials and devices
- New mechanisms/materials/devices
- Domains, domain walls, and domain engineering

The conference was organized by the School of Natural Sciences and Mathematics and Ural Center for Shared Use “Modern Nanotechnology” of the Ural Federal University.

The objective of SPM-2019-RCWDFM was to provide an international and interdisciplinary exchange of information on a wide range of topics related to modern state-of-the-art and future development of various Scanning Probe Microscopy techniques in different fields of science, as well as fundamentals and applications of dielectric and ferroelectric materials in order to ensure effective cooperation among scientists and specialists from universities, research institutions and industry.

More than 200 participants from 15 countries: Belarus, Brazil, Canada, China, France, Germany, Ireland, Japan, Korea, Netherlands, Poland, Portugal, Russia, Switzerland, and